

Issue Classification



Application/Control No.

10817177

Applicant(s)/Patent under Reexamination

JANG, DEOK HWAN

Examiner

Nguyen, Huy D

Art Unit

2617

ORIGINAL

CLASS

455

SUBCLASS

415

CROSS REFERENCE(S)

CLASS

455

410

411

418

SUBCLASS (ONE SUBCLASS PER BLOCK)

INTERNATIONAL CLASSIFICATION

CLAIMED

H 0 4 M

3 / 42

NON-CLAIMED

Huy Nguyen

(Assistant Examiner)

5/24/2006

(Date)

Total Claims Allowed:

2

(Legal Instruments Examiner)

5/25/06

(Date)

JOSEPH FEILD

(Principal Examiner)

5/23/06

O.G.

Print Claim(s)

1

O.G.

Print Figure

2